

**Notice of References Cited**Application/Control No.  
09/464,322Applicant(s)/Patent Under  
Reexamination  
KWON ET AL.Examiner  
Chris C. ChuArt Unit  
2815

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**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
	A	US-4926242-A	05-1990	Itoh et al.	257	720
	B	US-5359768-A	11-1994	Haley	29	840
	C	US-5683937-A	11-1997	Furukawa et al.	438	42
	D	US-5811317-A	09-1998	Maheshwari et al.	29	827
	E	US-5336364-A	08-1994	Takahama et al.	216	20
	F	US-6060778-A	05-2000	Jeong et al.	257	710
	G	US-5977626-A	11-1999	Wang et al.	257	707
	H	US-6146921-A	11-2000	Barrow	438	122
	I	US- -				
	J	US- -				
	K	US- -				
	L	US- -				
	M	US- -				

**FOREIGN PATENT DOCUMENTS**

*		Document Number	Date	Country	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY				
	N	JP-09199647-A	07-1997	Japan	Yano	-	-
	O	- -					
	P	- -					
	Q	- -					
	R	- -					
	S	- -					
	T	- -					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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